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Application/Control No.	Applicant(s)/Patent under Reexamination
10/720,123	LEE, HOI-JIN
Examiner	Art Unit
John D. Trimmings	2138

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Class	Subclass	Date	Examiner
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INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		) )
	DATE	EXMR
NPL Search: delay signal binning frequency.	3/15/2006	JPT
Dble Patenting: Negative.	3/15/2006	JPT
Class Search: 714/724,734,745,727, 368/120, 702/117, 324/763, 324/310, 368/113, 257/48, 331/57, 326/16. Text strategy attach.	3/15/2006	JPT
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